

**Search Notes**

Application/Control No.

10/706,050

Examiner

HOAN C. NGUYEN

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2871

**SEARCHED**

Class	Subclass	Date	Examiner
349	65	2/21/2006	CHN
362	31	2/21/2006	CHN
362	27	2/21/2006	CHN
362	332	2/21/2006	CHN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East search in US-PGPUB, USPAT, EPO, JPO, Derwent and IBM_TDB	2/21/2006	CHN